



ISC Audits & Reviews SC Summary (January 2017)

Doc.	Title	Results
5971;	Reapproval of SEMI T19-0311: Specification for Device Marking;	Passed
5973	Line Item Revision to SEMI E170-0416: Specification For Secured Foundation Of Recipe Management System (SFORMS)	
5973-LI1;	Revise the format of ‘Service Message Description Table’ in SEMI E170-0416.;	Passed
5973-LI2;	Correct editorial errors in ‘Table 46 Compliance Statement’ in SEMI E170-416.;	Passed
6043	Line Item Revision to SEMI MF28-0707 (Reapproved 0912) Test Methods for Minority Carrier Lifetime in Bulk Germanium and Silicon by Measurement of Photoconductivity Decay	
6043-LI1;	Correct title and concomitant text	Passed
6044	Line Item Revision to SEMI MF673-1014 Test Methods For Measuring Resistivity Of Semiconductor Wafers Or Sheet Resistance Of Semiconductor Films With A Noncontact Eddy-current Gauge	
6044-LI1;	Correct title and concomitant text;	Passed
6045	Line Item Revision to SEMI MF928-1014 Test Methods For Edge Contour Of Circular Semiconductor Wafers And Rigid Disk Substrates	
6045-LI1;	Correct title and concomitant text;	Passed
6046	Line Item Revision to SEMI MF1982-0714 Test Methods For Analyzing Organic Contaminants On Silicon Wafer Surfaces By Thermal Desorption Gas Chromatography	
6046-LI1;	Correct title and concomitant text	Passed
6047;	Reapproval of SEMI MF728-1106 (Reapproved 1111) Practice for Preparing an Optical Microscope for Dimensional Measurements ;	Passed
6048;	Reapproval of SEMI MF978-1106 (Reapproved 1111) Test Method for Characterizing Semiconductor Deep Levels by Transient Capacitance Techniques;	Passed
6135;	To add R1-8 to Related Information 1 INCREMENTAL IMPLEMENTATION STEPS of SEMI E170: Specification For Secured Foundation Of Recipe Management System (SFORMS).;	Passed
R4683J;	Ratification Ballot: Line Item Revision to SEMI S2-0715, Environmental, Health, and Safety Guideline for Semiconductor Manufacturing Equipment. Delayed Revisions Related to Chemical Exposure	



Doc.	Title	Results
R4683J-LI1	Revisions to SEMI S2 related to chemical exposure;	Passed
R5816B;	Ratification Ballot: Revision to SEMI F30-0710, Test Method for Verification of Purifier Performance Testing for Trace Gas Impurities and Particles at an Installation Site;	Passed
R5997A;	Ratification Ballot: Revision to SEMI C3-0413, Specification for Gases;	Passed

Line Item (LI)

All documents passed and will be forwarded to Standards Publications for final processing.

For more information, please contact the SEMI Standards Engineer/Coordinator (<http://www.semi.org/standards/contacts>) nearest you.

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Feb 1, 2017*